


<b>Search Notes</b>  	<b>Application/Control No.</b>  09605293	<b>Applicant(s)/Patent Under Reexamination</b>  CHAPEK, DAVID L.
	<b>Examiner</b>  Jay C Kim	<b>Art Unit</b>  2815

SEARCHED			
Class	Subclass	Date	Examiner
257	288, 410, E21.423, E21.625, E21.639, E29.273, E29.309	6/5/12	J.K.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR), See EAST Search History	6/5/12	J.K.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
257	288, 410, E21.423, E21.625, E21.639, E29.273, E29.309	6/5/12	J.K.

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